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Search Notes						

Application/Control No.	Applicant(s)/Patent under Reexamination
10/616,525	FUNK ET AL.
Examiner	Art Unit
J. Derek Rutten	2192

SEARCHED			
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
EAST (US-PGPUB; USPAT; EPO; JPO; IBM_TDB; DERWENT) - see search history printout	12/25/2007	JDR
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